

# AOI4S60-VB Datasheet

# N-Channel 650 V (D-S) Super Junction Power MOSFET

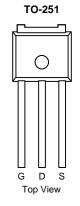
PRODUCT SUMMARY						
V <sub>DS</sub> (V) at T <sub>J</sub> max.	650					
R <sub>DS(on)</sub> at 25 °C (Ω)	V <sub>GS</sub> = 10 V	0.7				
Q <sub>g</sub> max. (nC)	25					
Q <sub>gs</sub> (nC)	2.0					
Q <sub>gd</sub> (nC)	2.7					
Configuration	Single					

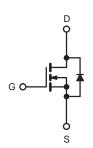
#### **FEATURES**

- ullet Low figure-of-merit (FOM)  $R_{on} \times Q_g$
- Low input capacitance (Ciss)
- Reduced switching and conduction losses
- Ultra low gate charge (Qq)
- Avalanche energy rated (UIS)

#### **APPLICATIONS**

- Server and telecom power supplies
- Switch mode power supplies (SMPS)
- Power factor correction power supplies (PFC)
- Lighting
  - High-intensity discharge (HID)
  - Fluorescent ballast lighting
- Industrial





N-Channel MOSFET

ABSOLUTE MAXIMUM RATINGS (T <sub>C</sub> = 25 °C, unless otherwise noted)						
PARAMETER			SYMBOL	LIMIT	UNIT	
Drain-Source Voltage			$V_{DS}$	650	\ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \	
Gate-Source Voltage			$V_{GS}$	± 30	V	
Continuous Prais Current /T _ 150 °C\	V <sub>GS</sub> at 10 V	$T_C = 25 ^{\circ}C$ $T_C = 100 ^{\circ}C$	C I <sub>D</sub>	7		
Continuous Drain Current (T <sub>J</sub> = 150 °C)	V <sub>GS</sub> at 10 V	T <sub>C</sub> = 100 °C		6	Α	
Pulsed Drain Current <sup>a</sup>			I <sub>DM</sub>	10		
Linear Derating Factor				1.67/1.5/0.3	W/°C	
Single Pulse Avalanche Energy b			E <sub>AS</sub>	86	mJ	
Maximum Power Dissipation			$P_{D}$	83/83/31	W	
Operating Junction and Storage Temperature Range			T <sub>J</sub> , T <sub>stg</sub>	-55 to +150	°C	
Drain-Source Voltage Slope	T <sub>J</sub> = 125 °C		50		1//	
Reverse Diode dV/dt <sup>d</sup>			dV/dt	4.5	- V/ns	
Soldering Recommendations (Peak Temperature) c for 10 s			300	°C		

#### Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature. b.  $V_{DD}=50$  V, starting  $T_J=25$  °C, L=28.2 mH,  $R_g=25$   $\Omega$ ,  $I_{AS}=3.5$  A.
- c. 1.6 mm from case.
- d.  $I_{SD} \le I_D$ ,  $dI/dt = 100 \text{ A/}\mu\text{s}$ , starting  $T_J = 25 \,^{\circ}\text{C}$ .



THERMAL RESISTANCE RATINGS					
PARAMETER	SYMBOL	TYP.	MAX.	UNIT	
Maximum Junction-to-Ambient	R <sub>thJA</sub>	-	63	°C/W	
Maximum Junction-to-Case (Drain)	R <sub>thJC</sub>	-	0.6	G/ VV	

PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT
Static					,	•	
Drain-Source Breakdown Voltage	V <sub>DS</sub>	V <sub>GS</sub> :	= 0 V, I <sub>D</sub> = 250 μA	650	-	-	V
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference	e to 25 °C, I <sub>D</sub> = 1 mA	-	0.65	-	V/°C
Gate-Source Threshold Voltage (N)	V <sub>GS(th)</sub>	V <sub>DS</sub> =	$V_{DS} = V_{GS}, I_D = 250 \mu\text{A}$		-	4	V
		V <sub>GS</sub> = ± 20 V		-	-	± 100	nA
Gate-Source Leakage	$I_{GSS}$		V <sub>GS</sub> = ± 30 V		-	± 1	μΑ
		V <sub>DS</sub> = 650 V, V <sub>GS</sub> = 0 V		-	-	1	
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> = 520 V	/, V <sub>GS</sub> = 0 V, T <sub>J</sub> = 125 °C	-	-	10	μA
Drain-Source On-State Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V	I <sub>D</sub> = 4 A	-	0.7	-	Ω
Forward Transconductance	9 <sub>fs</sub>	V <sub>DS</sub>	s = 30 V, I <sub>D</sub> = 4 A	-	16	-	S
Dynamic		•					
Input Capacitance	C <sub>iss</sub>		$V_{GS} = 0 V$ ,	-	360	-	
Output Capacitance	C <sub>oss</sub>	1	$V_{GS} = 0 \text{ V},$ $V_{DS} = 100 \text{ V},$		25	-	
Reverse Transfer Capacitance	C <sub>rss</sub>	f = 1 MHz		-	12	-	
Effective Output Capacitance, Energy Related <sup>a</sup>	C <sub>o(er)</sub>	V <sub>DS</sub> = 0 V to 520 V, V <sub>GS</sub> = 0 V		-	45	-	pF
Effective Output Capacitance, Time Related <sup>b</sup>	C <sub>o(tr)</sub>			-	62	-	
Total Gate Charge	Qg				25		
Gate-Source Charge	Q <sub>gs</sub>	$V_{GS} = 10 \text{ V}$ $I_D = 4 \text{ A}, V_{DS} = 520 \text{ V}$		-	2.0	-	nC
Gate-Drain Charge	$Q_{gd}$				2.7	-	
Turn-On Delay Time	t <sub>d(on)</sub>	V <sub>DD</sub> = 520 V, I <sub>D</sub> = 4 A,		-	25	-	
Rise Time	t <sub>r</sub>			-	55	-	ns
Turn-Off Delay Time	t <sub>d(off)</sub>		$V_{GS} = 10 \text{ V}, R_g = 9.1 \Omega$		70	-	] 115
Fall Time	t <sub>f</sub>				40	-	
Gate Input Resistance	$R_{g}$	f = 1 MHz, open drain		-	3.5	-	Ω
<b>Drain-Source Body Diode Characteristic</b>	S						
Continuous Source-Drain Diode Current	I <sub>S</sub>	MOSFET symbol showing the integral reverse p - n junction diode		-	-	7	
Pulsed Diode Forward Current	I <sub>SM</sub>			-	-	18	A
Diode Forward Voltage	V <sub>SD</sub>	T <sub>J</sub> = 25 °C, I <sub>S</sub> = 4 A, V <sub>GS</sub> = 0 V		-	-	1.5	V
Reverse Recovery Time	t <sub>rr</sub>	T <sub>J</sub> = 25 °C, I <sub>F</sub> = I <sub>S</sub> = 4 A, dl/dt = 100 A/µs, V <sub>R</sub> = 400 V		-	190	-	ns
Reverse Recovery Charge	Q <sub>rr</sub>			-	2.3	-	μC
Reverse Recovery Current	I <sub>RRM</sub>			<u> </u>	10	<del>-</del>	A

### Notes

- a.  $C_{oss(er)}$  is a fixed capacitance that gives the same energy as  $C_{oss}$  while  $V_{DS}$  is rising from 0 % to 80 %  $V_{DSS}$ . b.  $C_{oss(tr)}$  is a fixed capacitance that gives the same charging time as  $C_{oss}$  while  $V_{DS}$  is rising from 0 % to 80 %  $V_{DSS}$ .



# TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

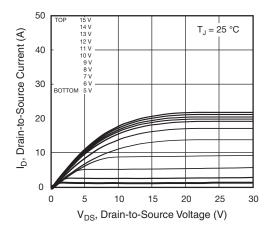


Fig. 1 - Typical Output Characteristics

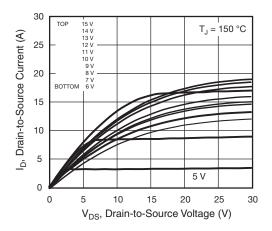


Fig. 2 - Typical Output Characteristics

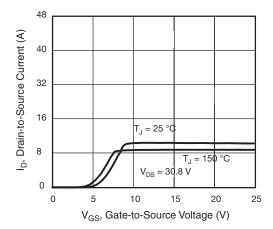


Fig. 3 - Typical Transfer Characteristics

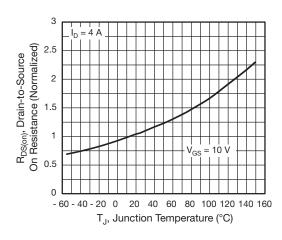


Fig. 4 - Normalized On-Resistance vs. Temperature

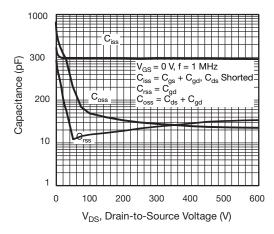


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

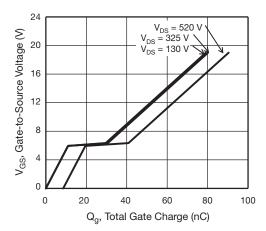


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

1000

100

10

0.1

0.01

I<sub>D</sub>, Drain Current (A)

Operation in this Are Limited by R<sub>DS(on)</sub>

T<sub>C</sub> = 25 °C

= 150 °C T<sub>J</sub> = 150 °C Single Pulse



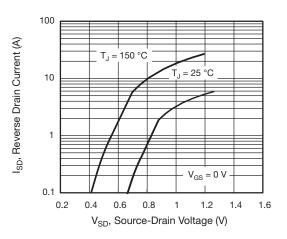


Fig. 7 - Typical Source-Drain Diode Forward Voltage

= Limited

н**і** 10 ms

1000



Fig. 8 - Maximum Safe Operating Area

 $\begin{array}{ccc} & 10 & 100 & 100 \\ V_{DS}\text{-} \ Drain -to-Source Voltage (V) \\ {}^* \ V_{GS} > minimum \ V_{GS} \ at \ which \ R_{DS(on)} \ is \ specified \end{array}$ 

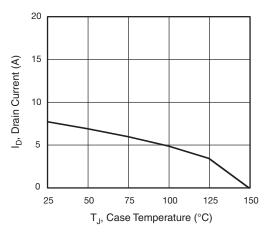


Fig. 9 - Maximum Drain Current vs. Case Temperature

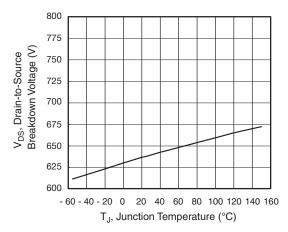


Fig. 10 - Temperature vs. Drain-to-Source Voltage

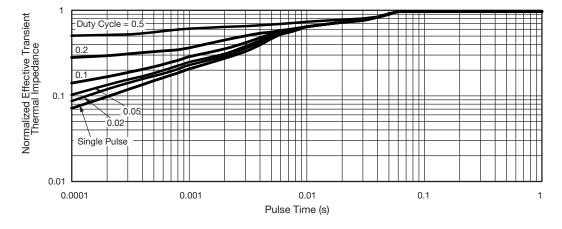


Fig. 11 - Normalized Thermal Transient Impedance, Junction-to-Case



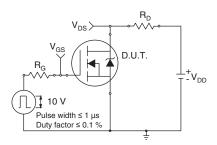


Fig. 12 - Switching Time Test Circuit

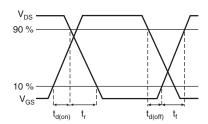


Fig. 13 - Switching Time Waveforms

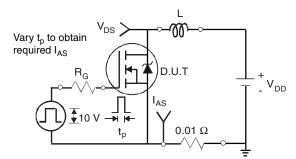


Fig. 14 - Unclamped Inductive Test Circuit

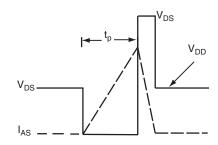


Fig. 15 - Unclamped Inductive Waveforms

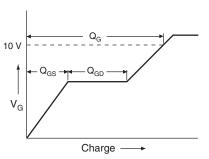


Fig. 16 - Basic Gate Charge Waveform

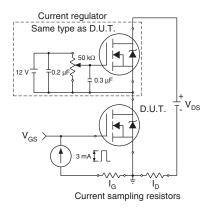
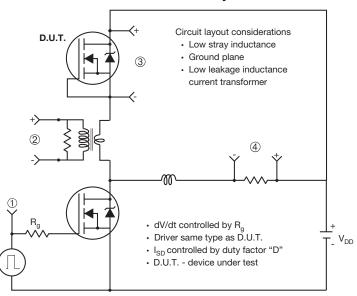


Fig. 17 - Gate Charge Test Circuit



#### Peak Diode Recovery dV/dt Test Circuit



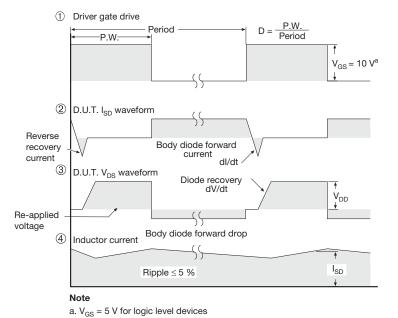
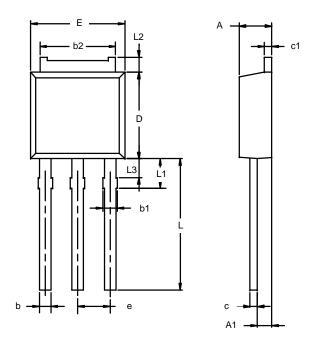


Fig. 18 - For N-Channel

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# TO-251AA (DPAK)



Note: Dimension L3 is for reference on
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	MILLIM	IETERS	INCHES		
Dim	Min	Max	Min	Max	
Α	2.21	2.38	0.087	0.094	
A1	0.89	1.14	0.035	0.045	
b	0.71	0.89	0.028	0.035	
b1	0.76	1.14	0.030	0.045	
b2	5.23	5.43	0.206	0.214	
С	0.46	0.58	0.018	0.023	
с1	0.46	0.58	0.018	0.023	
D	5.97	6.22	0.235	0.245	
Е	6.48	6.73	0.255	0.265	
е	2.28 BSC		0.090	BSC	
L	8.89	9.53	0.350	0.375	
L1	1.91	2.28	0.075	0.090	
L2	0.89	1.27	0.035	0.050	
L3	1.15	1.52	0.045	0.060	

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